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PATENT  
Attorney Matter No. 6427-65559-01

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

**In re application of:** James F. Orsillo

**Date Mailed** June 26, 2007

**Patent No.** 7,053,646

**Issued:** May 30, 2006

**Application No.** 10/695,245

**Filed:** October 27, 2003

**Confirmation No.** 4337

**For:** APPARATUS AND METHOD FOR USE  
IN TESTING A SEMICONDUCTOR  
WAFER (ADAPTOR PLATE FOR 300MM  
PROBE STATION)

**Examiner:** Jermele M. Hollington

**Art Unit:** 2829

**Attorney Reference No.** 6427-65559-01

**Certificate**  
**JUL 23 2007**  
**of Correction**

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LETTER OF CORRECTION

The following printing errors were noted in comparing the printed patent with the papers  
in the attorneys' files:

In the Claims:

Column 14, line 9, "first and second plate" should be --first and second plates--.

Column 16, line 5, "second semiconductor" should be --second semiconductor wafer--.


All of the above errors are not considered to be of major significance. Applicant requests that this document be included in the file wrapper of the subject patent to make formal notice of the errors.

Respectfully submitted,

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cc: Docketing